

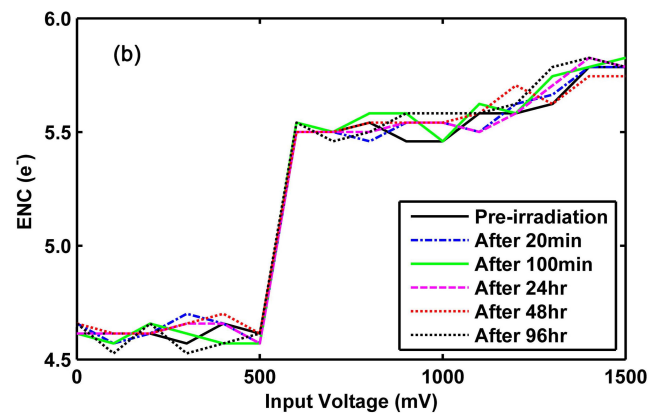
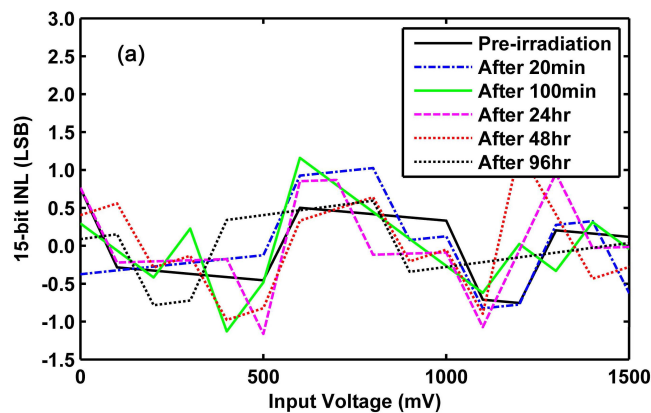
# Corrections to “Design and Characterizations of the Radiation-Hardened XCR4C ASIC for X-Ray CCDs for Space Astronomical Applications”

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In the above article [1], on p. 1181, Fig. 7 appears the same as Fig. 6, which is incorrect. Instead, Fig. 7 should appear as below.

## REFERENCES

- [1] B. Lu *et al.*, “Design and characterizations of the radiation-hardened XCR4C ASIC for X-ray CCDs for space astronomical applications,” *IEEE Trans. Nucl. Sci.*, vol. 67, no. 6, pp. 1175–1184, Jun. 2020.



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